

# yelo

## Burn-in Expertise

Low power laser diode burn-in

# Y4000



### ABOUT THE SYSTEM

Easily test the reliability of low power laser devices with Yelo's Y4000 Standard burn-in and life-test system. It will quickly identify defective devices so you can prevent them reaching your customers. The Y4000 software automates threshold calculations and has an expandable capacity which helps work through tests more productively.

The Y4000 is ideal for testing in a production environment. It is capable of providing probed burn-in for 100G, 400G & 800G network devices. Individual laser components can be tested with in-situ LIV measurements\* during burn-in test cycles.

### PROTECT YOUR LASER

The Yelo Y4000 product has a number of key features to protect your laser.

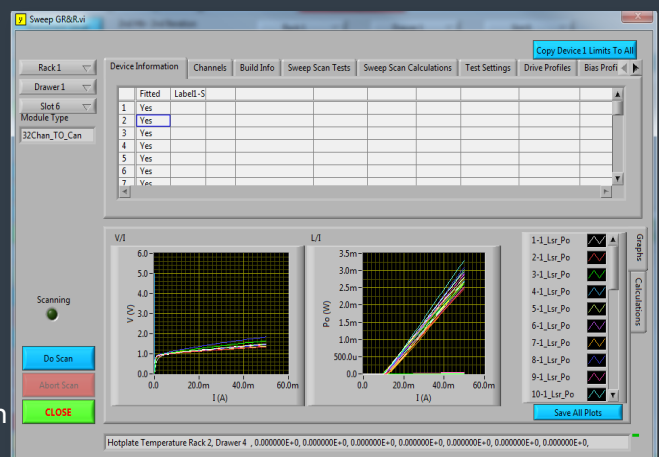
- Programmable current ramp on and off to reduce thermal shock
- Over current protection
- Over and under temperature protection
- Controlled shutdown on power failure

### BURN-IN SOFTWARE

The screenshot is an example of Yelo's capability showing graphical output from post burn-in functional tests that were performed on 32 TOcan lasers.

LEFT GRAPH: The voltage drop across the lasers changes as more current is driven into the laser. One laser is showing an open circuit failure (blue line), displayed as a straight 5 Volt measurement.

RIGHT GRAPH: The graph on the right shows an LIV curve, where the devices have begun to lase at approximately 10mA. Threshold calculations are automated by the system software.



\* dependant on system configuration

### OPERATOR SAFETY

Yelo manufacture systems with the operator at the forefront of the design. The low power laser diode systems feature:

- Interlock to stop accidental start of tests
- Operator health and safety
- CE Compliant

### DEVICES

- ✓ Laser Diodes
- ✓ Avalanche Photodiodes
- ✓ Integrated Devices
- ✓ Photodiodes



# Y4000

## System Features & Architecture

### SYSTEM FEATURES

- Test TOcan, COS, COC, BFLY, VCSEL's, Photonic Integrated Devices and much more
- Capable of burn-in for SFP, SFP+ transceiver electronics in 100G, 400G & 800G network devices
- Channel Density from 384 to 5120
- Ideal for testing low power devices up to 2000mA
- Used for Burn-in, Life-test & vendor qualification
- Custom built to your specification with NIST standard instruments

### ARCHITECTURE



Fixtures



Drawers



Racks

### SPECIFICATION

Rack style	42U
Rack size	800mm (W) x 900mm (D) x 2100mm (H)* <small>*exclusive of traffic light</small>
Temperature Range	20 - 90°C
Temperature Control	TEC/Water Cooling Technology
Maximum Current per Device	up to 2000mA
Capacity	384 to 5120* <small>*Dependant on current setting</small>